

Plasma accumulation effects in Extreme Ultra-Violet generated plasmas

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Introduction

In order to meet the demand of increasing computer speed and memory capacity, industries are striving to reduce the size of computer chips. This miniaturization can be achieved by reducing the wavelength in lithography machines to Extreme Ultra-Violet (EUV, 92 eV). The low-pressure (around 1 Pa) transparent background gas (e.g. H₂ and He) in the lithography machine is partially ionized by the absorption of EUV photons. The study of these low-density (10¹⁵ m⁻³) pulsed plasmas is interesting and experimentally challenging.

Goal

Study the accumulation of electron density in EUV induced plasmas.

Experimental set-up

- Tin-based LDP source
- Short (sub-µs) EUV pulse
- Frequency: ۲
 - 10 kHz with 50% duty cycle (50 Hz)
 - 500 Hz with 100% duty cycle
- Inband energy (13.5 nm \pm 2%) about 12 μ J per pulse



Microwave cavity resonance spectroscopy



Plasma accumulation

TU



Elementary **Processes in**

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Gas discharges

Conclusions & Outlook

- Plasma accumulation visible at high frequencies
- Accumulation predictable from low frequency measurement •
- Repeat experiments in hydrogen •
- Perform optical emission spectroscopy experiments

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